

FORM PTO 1449 (modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)				ATTY DOCKET NO. 00862.023,57		APPLICATION NO. 10/619,576	
				APPLICANT Hiroshi Watanabe et al.			
				FILING DATE SEP 16, 2003			
				GROUP N.Y.A. 1746			

U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
SC		5,520,744	05/28/96	Fujikawa et al.	134	11	
SC		4,746,397	05/24/88	Maeda et al.	156	637	
SC		5,331,987	07/26/94	Hayashi et al.	134	102.1	

FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
SC	JP	3-169013	07/22/91	Japan			Abstract
SC	JP	5-275412	10/22/93	Japan			Abstract
SC	JP	6-216101	08/05/94	Japan			Abstract
SC	JP	6-326073	11/25/94	Japan			Abstract
SC	JP	7-130699	05/19/95	Japan			Abstract

OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)		
SC		Takeshi Hattori, <u>Silicon Wafer Surface Cleaning Technique New Edition</u> , pp. 450-463 (2001).

EXAMINER /Sharidan Carrillo/	DATE CONSIDERED 07/23/2006
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 809; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

FORM PTO 1449 (modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)		ATTY DCKET NO. 00862-023157 APPLICANT Hiroshi Watanab et al. FILING DATE July 16, 2003		APPLICATION NO. 10/619,576 GROUP N.Y.A. 1746	
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U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
SC	JP	2002-16119	01/18/02	Japan			Abstract
SC	JP	2002-231688	09/16/02	Japan			Abstract
SC	JP	62-165939	07/22/87	Japan			Abstract
SC	JP	7-19765 B2	03/06/95	Japan			Abstract

OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)

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